



QUALITY
SEMICONDUCTOR, INC.

High-Speed CMOS 3.3V 8-Bit Buffers/Line Drivers

QS74LVC541A

FEATURES/BENEFITS

- 5V tolerant inputs and outputs
- $10\mu A$ I_{CCQ} quiescent power supply current
- Hot insertable
- 2.0V–3.6V V_{CC} supply operation
- $\pm 24mA$ balanced output drive
- Power down high impedance inputs and outputs
- $t_{PD} = 4.0$ ns max.
- Input hysteresis for noise immunity
- Meets or exceeds JEDEC Standard 36 specifications
- Multiple power and ground pins for low noise
- Operating temperature range:
–40°C to 85°C
- Latch-up performance exceeds 500mA
- ESD performance:
Human body model > 2000V
Machine model > 200V
- Packages available:
20-pin QSOP
20-pin SOIC

DESCRIPTION

The LVC541A is an 8-bit buffer/line driver with three-state outputs that is ideal for driving high capacitance loads such as memory address and data buses. The 3.3V LVC family features low power, low switching noise, and fast switching speeds for low power portable applications as well as high-end, advanced workstation applications. 5V tolerant inputs and outputs allow these LVC products to be used in mixed 5V and 3.3V applications. To accommodate hot-plug or live insertion applications, these products are designed not to load an active bus when V_{CC} is removed. However, during power up or power down sequence, \overline{OE} should be tied to V_{CC} to ensure high-impedance state on the outputs.

Figure 1. Functional Block Diagram

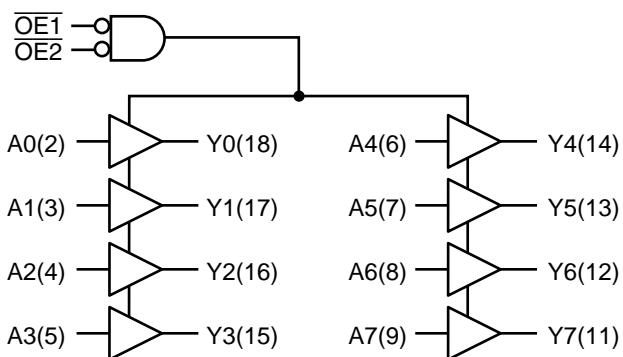


Figure 2. Pin Configuration
(All Pins Top View)

SSOP, QSOP

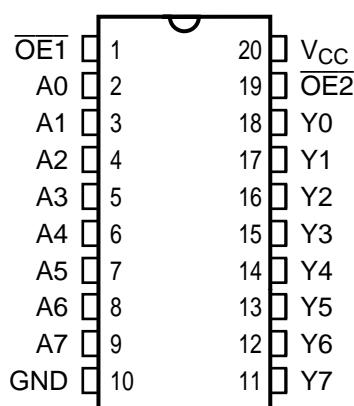


Table 1. Pin Description

Name	I/O	Description
A7-A0	I	Data Inputs
Y7-Y0	O	Data Outputs
OE1, OE2	I	Three-State Output Enable

Table 2. Function Table

OE1	OE2	Input A	Output Y	Function
H	X	X	Hi-Z	Disable Outputs
X	H	X	Hi-Z	
L	L	L	L	Enable Outputs
L	L	H	H	

Table 3. Absolute Maximum Ratings

Supply Voltage to Ground	-0.5V to 7.0V
DC Output Voltage V _{OUT}	
Outputs HIGH-Z	-0.5V to 7.0V
Outputs Active	-0.5V to V _{CC} + 0.5V
DC Input Voltage V _{IN}	-0.5V to 7.0V
DC Input Diode Current with V _{IN} < 0	-50mA
DC Output Diode Current	
V _O < 0	-50mA
V _O > V _{CC}	50mA
DC Output Source/Sink Current (I _{OH} /I _{OL})	±50mA
DC Supply Current per Supply Pin	±100mA
DC Ground Current per Ground Pin	±100mA
T _{STG} Storage Temperature	-65°C to 150°C

Note: Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to this device resulting in functional or reliability type failures.

Table 4. Recommended Operating Conditions

Symbol	Parameter		Min	Max	Unit
V_{CC}	Supply Voltage, Operating		2.0	3.6	V
	Supply Voltage, Data Retention Only		1.5	3.6	
V_{IH}	Input HIGH Voltage	$V_{OL} = 2.7$ to 3.6V	2.0	—	V
V_{IL}	Input LOW Voltage	$V_{CC} = 2.7$ to 3.6V	—	0.8	V
V_{IN}	Input Voltage		0	5.5	V
V_{OUT}	Output Voltage in Active State		0	V_{CC}	V
	Output Voltage in "OFF" State		0	5.5	
I_{OH}	Output Current HIGH	$V_{CC} = 3.0$ – 3.6V	—	-24	mA
		$V_{CC} = 2.7\text{V}$	—	-12	
I_{OL}	Output Current LOW	$V_{CC} = 3.0$ – 3.6V	—	24	mA
		$V_{CC} = 2.7\text{V}$	—	12	
$\Delta t/\Delta v$	Input Transition Slew Rate		—	10	ns/V
T_A	Operating Free Air Temperature		-40	85	°C

Table 5. DC Electrical Characteristics Over Operating RangeIndustrial Temperature Range, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Min	Typ ⁽¹⁾	Max	Unit
V_{OH}	Output HIGH Voltage	$V_{CC} = 2.7\text{V}$, $I_{OH} = -100\mu\text{A}$	$V_{CC} = 0.2$	—	—	V
		$V_{CC} = 2.7\text{V}$, $I_{OH} = -12\text{mA}$	2.2	—	—	
		$V_{CC} = 3.0\text{V}$, $I_{OH} = -12\text{mA}$	2.4	—	—	
		$V_{CC} = 3.0\text{V}$, $I_{OH} = -24\text{mA}$	2.2	—	—	
V_{OL}	Output LOW Voltage	$V_{CC} = 2.7\text{V}$, $I_{OL} = 100\mu\text{A}$	—	—	0.2	V
		$V_{CC} = 2.7\text{V}$, $I_{OL} = 12\text{mA}$	—	—	0.4	
		$V_{CC} = 3.0\text{V}$, $I_{OL} = 24\text{mA}$	—	—	0.55	
V_{IK}	Input Clamp Voltage	$V_{CC} = 2.7\text{V}$, $I_{IN} = -18\text{mA}$	—	-0.7	-1.2	V
I_I	Input Leakage Current	$V_I = 0\text{V}$, $V_I = 5.5\text{V}$, $V_{CC} = 3.6\text{V}$	—	—	± 1.0	μA
I_{OZ}	High-Z I/O Leakage	$V_O = 0\text{V}$, $V_O = 5.5\text{V}$, $V_I = V_{IH}$ or V_{IL} , $V_{CC} = 3.6\text{V}$	—	—	± 1.0	μA
I_{OFF}	Power Off Leakage	$V_{CC} = 0\text{V}$, V_I or $V_O = 5.5\text{V}$	—	—	10	μA
I_{CC}	Quiescent Power Supply Current	$V_{CC} = 3.6\text{V}$, $V_{IN} = V_{CC}$ or GND	—	0.1	10	μA
ΔI_{CC}	Quiescent Power Supply Current per Control Inputs at TTL HIGH	$V_{CC} = 3.6\text{V}$, $V_{IN} = V_{CC} - 0.6\text{V}^{(2)}$	—	2.0	3.0	μA

Notes:

1. Typical values are at $V_{CC} = 3.3\text{V}$ and $T_A = 25^\circ\text{C}$.
2. Per TTL driven input. All other inputs at V_{CC} or GND.

Table 6. Dynamic Switching Characteristics

Symbol	Parameter	Test Conditions			Typ ⁽¹⁾	Unit
V_{OLP}	Quiet Output Dynamic Peak V_{OL}	$C_L = 50\text{pF}$, $V_{CC} = 3.3\text{V}$	$V_{IH} = 3.3\text{V}$, $V_{IL} = 0\text{V}$		0.8	V
V_{OLV}	Quiet Output Dynamic Valley V_{OL}	$C_L = 50\text{pF}$, $V_{CC} = 3.3\text{V}$	$V_{IH} = 3.3\text{V}$, $V_{IL} = 0\text{V}$		0.8	V
C_{PD}	Power Dissipation	$C_L = 50\text{pF}$, $f = 10\text{MHz}$, $V_{CC} = 3.6 \pm 0.3\text{V}$	Output Enable		20	pF
			Output Disable		4	

Note:

1. Typical values are at $V_{CC} = 3.3\text{V}$ 25°C ambient.

Table 7. Capacitance⁽¹⁾

Symbol	Pins	Conditions	Typ	Unit
C_{IN}	Input Capacitance	$V_{IN} = 0\text{V}$, $V_{OUT} = 0\text{V}$, $f = 1\text{MHz}$	7.0	pF
$C_{I/O}$	I/O Capacitance	$V_{IN} = 0\text{V}$, $V_{OUT} = 0\text{V}$, $f = 1\text{MHz}$	8.0	pF

Note:

1. Capacitance is characterized but not production tested.

Table 8. Switching Characteristics Over Operating Range

Industrial Temperature Range, $T_A = -40^\circ\text{C}$ to 85°C .

$C_{LOAD} = 50\text{pF}$, $R_{LOAD} = 500\Omega$ unless otherwise noted.

Symbol	Description ⁽¹⁾	$V_{CC} = 3.3 \pm 0.3\text{V}$		$V_{CC} = 2.7\text{V}^{(2)}$		Unit
		Min	Max	Min	Max	
t_{PD}	Propagation Delay Ai to Yi	1.5	5.1	1.5	5.6	ns
t_{EN}	Output Enable Time \overline{OE} to Yi	1.5	7.0	1.5	7.5	ns
t_{DIS}	Output Disable Time ⁽²⁾ \overline{OE} to Yi	1.5	7.0	1.5	7.7	ns
$t_{SK(O)}$	Output Skew ⁽³⁾	—	0.5	—	—	ns

Notes:

1. Minimums guaranteed but not tested. See Test Circuit and Waveforms.
2. Guaranteed by characterization.
3. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by characterization but not production tested.

TEST CIRCUIT AND WAVEFORMS

Figure 3. Test Circuit

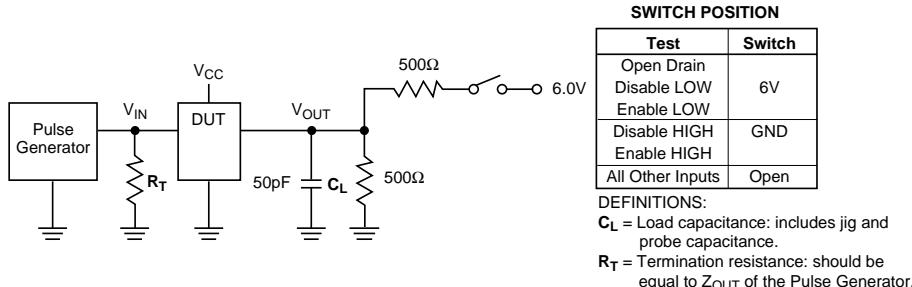


Figure 4. Setup, Hold, and Release Timing

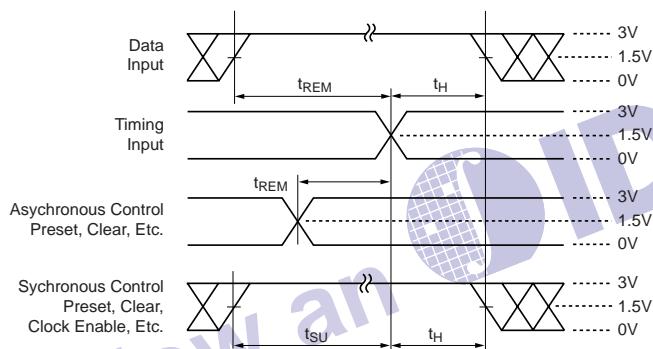


Figure 6. Pulse Width

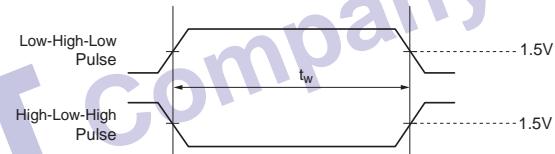


Figure 5. Enable and Disable Timing

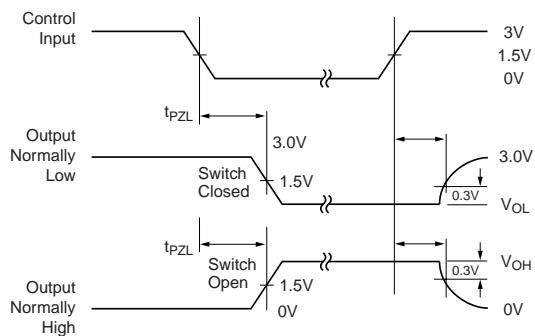
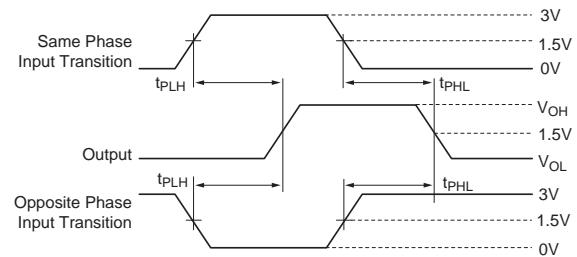


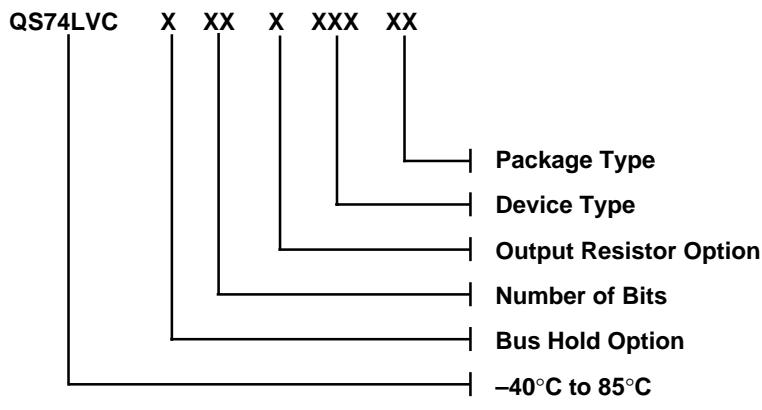
Figure 7. Propagation Delay



Notes:

1. Input Control Enable = LOW and Input Control Disable = HIGH.
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $Z_{OUT} \leq 50\Omega$; $t_F, t_R \leq 2.5\text{ns}$.

ORDERING INFORMATION



Bus Hold Option:
Blank – No Bus Hold

Number of Bits:
Blank – 8-Bit

Output Resistor Option:
Blank – No Output Resistor

Device Type:
541

Package Type:
Q – QSOP, 150 mil
SO – SOIC, 300 mil

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